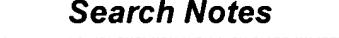


Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/517,443	SHIMIZU ET AL.
	Examiner	Art Unit
	Alex Epshteyn	3714

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner